

**Digital design flow with test activities**

Diener, Karl-Heinz; Elst, G.; **Ivask, Eero; Jervan, Gert**; Peng, Z.; **Raik, Jaan; Ubar, Raimund-Johannes** VILAB User Forum 2000 / [11] p

**Hierarchical defect level test quality analysis**

Blyzniuk, M.; Cibakova, Tatiana; Gramatova, Elena; Kuzmich, W.; Lobur, M.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** VILAB User Forum 2000 / [11] p